

**SCHOTTKY DIODES KDN-08020.**  
PRELIMINARY



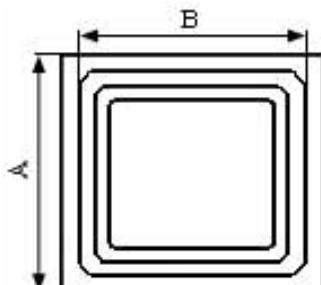
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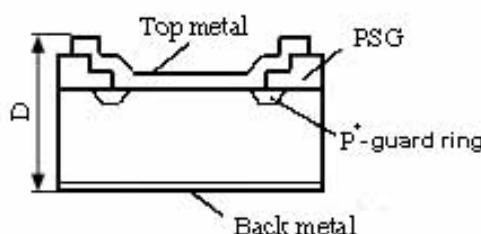
**VSP-MIKRON**

**8A/20V. Die Size-73mil.**

Electrical Characteristics	Symbol	Unit	Spec. limit	Die Sort
Breakdown Voltage @ $I_R=10\text{mA}$	$V_{BR}$	V	20	25
Average Rectified Forward Current	$I_{F(AV)}$	A	8,0	-
DC Forward Voltage @ $25^\circ\text{C}$ , $I_F=8,0\text{A}$	$V_F$	V	0,50	0,48
Maximum Reverse Current  @ $25^\circ\text{C}$ , $V_R=25\text{V}$ $25^\circ\text{C}$ , $V_R=20\text{V}$ $125^\circ\text{C}$ , $V_R=20\text{V}$	$I_R$	mA	- 0,200 0,130 70,0	0,200 0,130 60,0
Peak Forward Surge Current 8,3ms single half sine-wave superimposed on rated load (JEDEC METHOD)	$I_{FSM}$	A	135	-
Peak Repetitive Reverse Surge Current @ $2,0\mu\text{s}$ , $f=1\text{kHz.}$ , $T_J<150^\circ\text{C.}$	$I_{RRM}$	A	3,5	
Electrostatic Discharge Voltage. JEDEC Method. ESD HBM. Contact.	ESD	kV	$\pm 8$ (contact)	
Voltage Rate of Change	$dV/dt$	V/ $\mu\text{S}$	10.000	
Operating Junction Temperature	$T_J$	°C	150	



DIM	ITEM	µm
$A_x$	Wafer Form Die Size	1850
$A_y$		1850
$B_x$	Top Metal Size	1710
$B_y$		1710
D	Thickness	350max.
Scribe line Width		80



*Top metal:* a) **Al** – for Wire Bonding;  
b) **Al-Ni-Ag**; - for Soldering.

*Backside metal:* **Ti-Ni-Ag**.

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